ELECTRICAL AND MECHANICAL ENGINEERING REGULATIONS

#### RESTRICTED

**TELECOMMUNICATIONS** 

-Z-560/1 2630.

390

# CRYSTAL TEST SET, TYPE AM 193

# DATA SUMMARY

To measure the activity of crystals operating on frequencies between 3Mc/s and  $10Mc/s. \label{eq:crystals}$ 

#### DESCRIPTION

An oscillator in which the oscillatory circuit can be either the crystal under test, or a variable Colpitts circuit. Similar operating conditions are set up for these in turn, and the tuning condenser of the Colpitts circuit is calibrated in equivalent parallel resistance.

#### PHYSICAL DATA

Weight: 24lb. Height: 5\frac{1}{4}in. Length: 8\frac{1}{4}in. Width: 19in.

#### **REMARKS**

May be either rack or bench mounting.

#### **FREQUENCY**

Coverage: 3 to 10 Mc/s. The crystal activity can be measured with three alternative input capacities, 20, 30 or 50pF, selected by means of a switch.

#### POWER REQUIREMENTS AND CONSUMPTION

80, 110, 115, 180 or 230V A.C., 2,000 to 50c/s. Approx. 65W.

#### **VALVES**

ARP 35 AW 4

#### SPECIAL FACILITIES

An output socket is provided on the front panel, coupled by stray capacity effects to the oscillatory circuit, and the output can be used to measure the crystal frequency by feeding into a wavemeter.

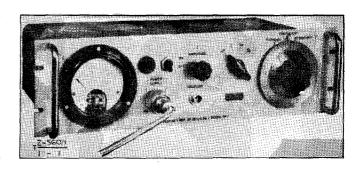


FIG. 1- General view of equipment

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# CRYSTAL TEST SET, A.M. 193

## OPERATORS' INSTRUCTIONS

## Preliminary

1. Open the case and check that the valve and voltage stabilizer are held securely in their sockets, and that the mains transformer is adjusted to the correct tapping. Replace in the case and screw up.

## Operation

- 2. Switch on and allow the test set to warm up for 5 minutes.
- 3. Place the crystal unit to be tested in the crystal socket, and turn the selector switch to the 30pF position, which is the normal testing position. Crystals which require testing with the selector switch in the 20pF or 50pF position will very rarely be met.
- 4. Adjust the AMPLITUDE control until the meter reads exactly  $50\mu A$  (half-scale deflection).
- 5. Turn the selector switch to the Z position and adjust the EQUIVALENT PARALLEL RESISTANCE dial until the meter again reads  $50\mu$ M.
- 6. Repeat operations 3 and 4, and if any change in adjustment is necessary, repeat operation 5 also. The dial now indicates directly the equivalent parallel resistance of the crystal unit, in thousands of ohms.
- 7. Compare the value obtained with the specification curve given in the accompanying graph, Fig. 1

#### Notes

- 8. If it is not possible to adjust the meter reading to  $50\mu\text{A}$  by means of the AMPLITUDE control, it is permissible to use a lower reference level say,  $30\mu\text{A}$ , provided the same procedure is used as in the operations 3, 4 and 5.
- 9. For convenience in measuring the frequency at which the crystal is oscillating a socket is provided labelled OUTPUT. This provides loose coupling to the crystal circuit and a direct lead can be taken from it to a suitable wavemeter.

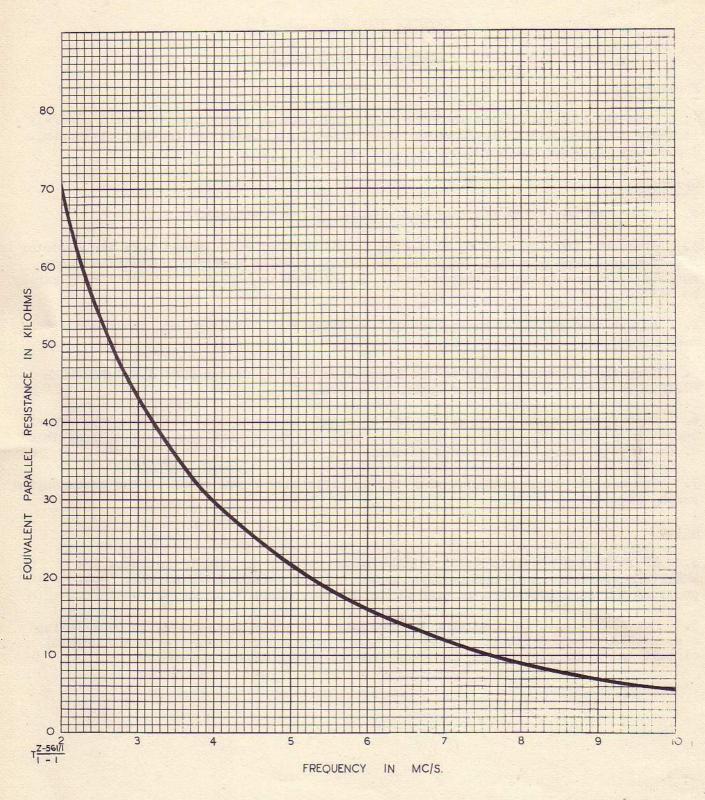


Fig. 1 - Low limit for crystal units in the range 2-10Mc/s

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# CRYSTAL TEST SET, TYPE A.M.193

#### GENERAL DESCRIPTION

#### INTRODUCTION

- 1. The purpose of the Test set A.M.193 is to provide an indication of the activity of quartz oscillator crystals so that crystals which fail to reach satisfactory standards can be rejected and be replaced by more efficient specimens.
- When placed in an oscillatory circuit, usually between grid and anode or grid and earth in a pentode stage, the crystal acts like an inductor with a very high Q and, in parallel with the capacitance presented by the valve, it forms a resonant circuit. To the crystal, the valve stage looks like a capacitance of from 15pF to 60pF, depending upon the type of circuit used. To the valve, the crystal looks like an inductance in parallel with a resistance, and the higher the resistance, the better the crystal, i.e., the higher the Q value of the resonant circuit. In practice, for the range of crystals oscillating between 3Mc/s and 10Mc/s, usual values of parallel resistance are from  $5\text{k}\Omega$  to  $150\text{k}\Omega$ ,  $\epsilon$  these are the values for which the Test set A.M.193 has been designed.
- 3. The method of testing used is to place the crystal under test into a typical oscillatory stage and to measure the grid current flowing. Provision is made for three input capacities of 20, 30 or 50pF, selected by means of a switch. The current is controlled within limits by means of an amplitude control, which varies the screen voltage of the oscillator valve. In practice it is used to set up a suitable meter reading of about half-scale which is then noted. The crystal oscillates under low-drive conditions. The anode circuit of the stage is not tuned in any way.
- 4. Having noted the meter reading with the crystal in circuit, the selector switch is turned to the Z position in which the crystal is replaced in the oscillatory valve stage by a built in Colpitts type resonant circuit. This can be tuned by means of a variable condenser (ClO) until the meter reading of the grid current is the same as it was when the crystal was being tested. The calibrated dial of the tuning condenser (ClO) then indicates directly the equivalent parallel resistance of the crystal.

Note: In the Z position the frequency of oscillation is not that of the crystal.

- 5. The power supply is from A.C. mains; 80V to 240V tappings are provided on the transformer. The output from the transformer secondary is taken to a voltage-doubler stage, using two metal rectifiers, and then to an AW4 voltage stabilizer. A dial lamp LP1 is fitted and indicates when the power supply is switched on.
- 6. The 3-hole socket provided on the front panel takes the standard Air Ministry type of crystal holder. A further concentric socket marked COUPLING is connected by stray capacitance only to the oscillatory circuit and can be used as a R.F. output to a radio receiver or wavemeter if it is desired to check the frequency of oscillation of the crystal under test.
- 7. The instrument is designed to be rack-mounted on a standard 19 in. rack, but can also be used as a bench-mounted instrument.

## TECHNICAL DESCRIPTION

- 8. There are four circuit conditions, selected by means of the selector switch, and they are best explained by reference to the simplified circuit diagrams in Figs. 1,, 2, 3 and 4.
  - (a) 20pF position (Fig. 1)
    The crystal is connected across a simple Colpitts type circuit consisting of C6 and C5, which are carefully balanced.

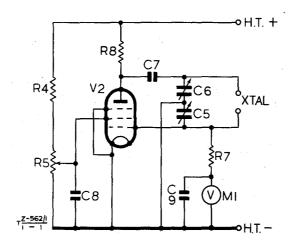


Fig. 1 - Selector switch in 20pF position

Note:- R5 is the amplitude control, V2 is an ARP35 and M1 is a 0-100 microammeter with a 3 in. scale.

(b) 30pF position (Fig. 2)
Additional capacitance is added by C15 and C16, which are carefully balanced.

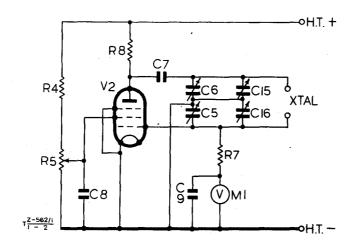


Fig. 2 - Selector switch in John position

(c) 50pF position (Fig. 3)
Additional capacitance is added by C13, C14 and C17, which are carefully balanced.

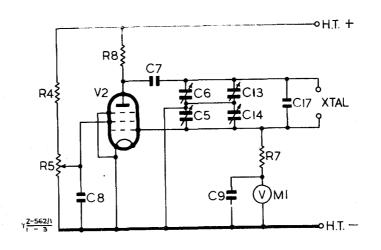


Fig. 3 - Selector switch in 50pF position

(d) Z Position (Fig. 4)
In this position the crystal is earthed on both sides and a variable Colpitts resonant circuit replaces it. C10 is the tuning condenser and has a dial calibrated in thousands of chms. C11 and C12 are used to align the circuit at each end of the calibrated scale. C11 is used at the low-n resistance end of the scale and C12 at the high-resistance end.

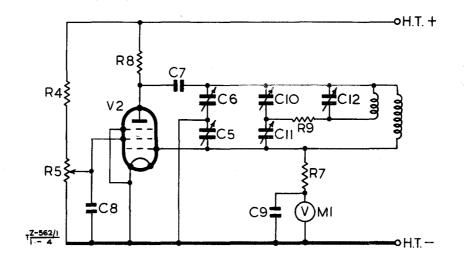


Fig. 4 - Selector switch in Z position

Note: The next page is page 1001

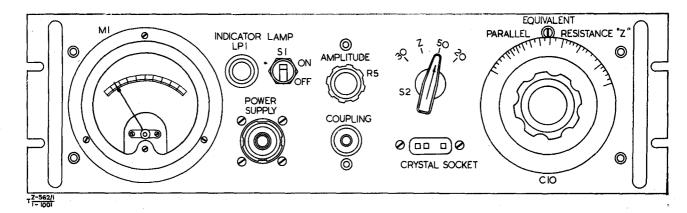
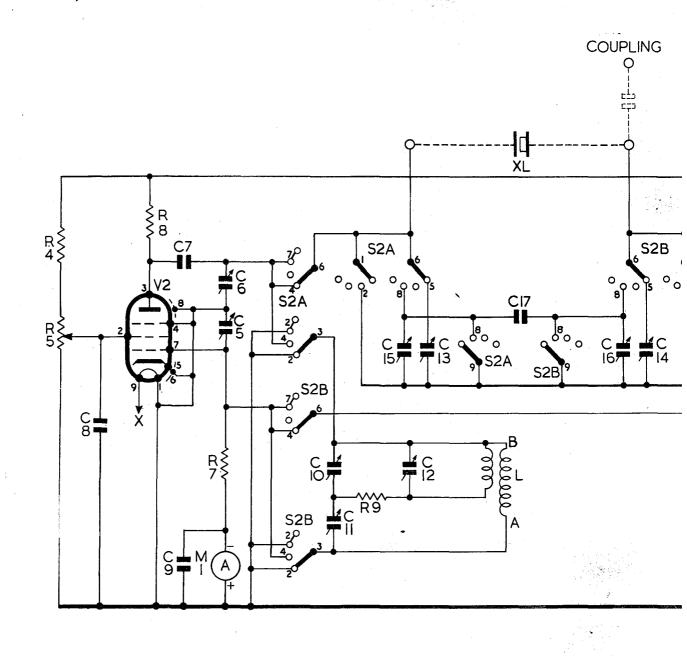


Fig. 1001 - Front panel layout

	0.			
Circuit reference	Value	Rating	Tolerance	Remarks
RESISTORS R1 R2 R3 R4 R5 R7 R8 R9 R10 R11	2k 2k 220k 51k 50k 100k 51k 1k 51k 100k	₹M ₹M 1M ₹M 1M 1OM 1OM	20% 20% 20% 20% 15550 155551 11±1+1+1	Potentiometer
C1 C2 C3 C5 C6 C7 C8 C9 C10 C11 C12 C13 C14 C15 C16 C17	2 F 2 F 4 F 50pF 50pF 0.001 F 0.01 F 0.1 F 100pF 50pF 3-30pF 50pF 50pF 50pF 50pF	350V 350V 350V 250V 500V 500V	± 20% ± 20% ± 20% ± 5%	Variable  " " Trimmer Variable " "

#### MISCELLANEOUS

Circuit reference	Туре	Circuit reference	Type		
T1 S1 S2 W1) W2)	Mains transformer Switch, double-pole, sin- gle-throw Switch, change-over Rectifier, selenium, half- wave	LP1 M1 V1 V2	Pilot lamp 6.3V 0-100 microammeter 3½ in. moving-coil AW4 ARP35		



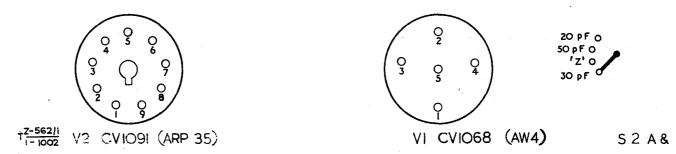
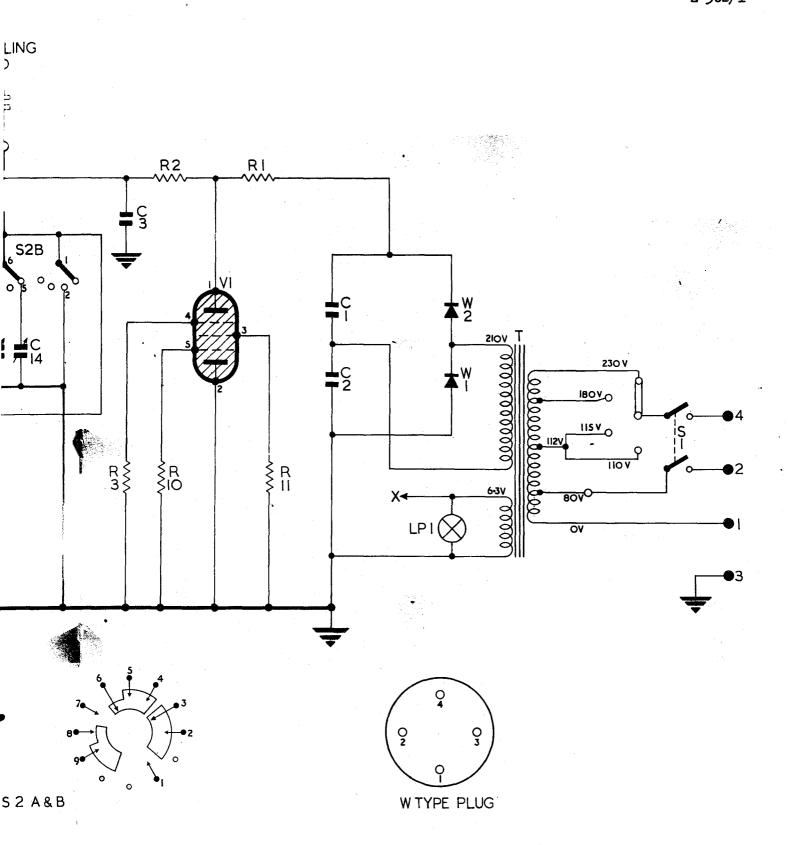


Fig. 1002 - Ci



OO2 - Circuit diagram

ELECTRICAL AND MECHANICAL ENGINEERING REGULATIONS

# CRYSTAL TEST SET, TYPE A.M. 103

#### FIRST ECHELON WORK

#### ROUTINE MAINTENANCE

1. Routine maintenance is limited to ensuring that plugs and sockets are kept clean and that the various control knobs are not allowed to work loose. It is important that the calibrated dial EQUIVALENT PARALLEL RESISTANCE is not readjusted in any way.

## Repairs

- 2. The valve V2 may be changed without affecting the performance of the equipment.
- 3. If the valve V1 is changed, it will be necessary to check the H.T. voltage. This should be  $280V \pm 5V$ .
- 4. No other adjustments are permitted. On no account may any of the preset or trimmer condensers be changed or readjusted.

END

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# CRYSTAL, TEST SET, TYPE A.M. 193

## TECHNICAL HANDBOOK - SECOND TO FOURTH ECHELON WORK

Note: This issue, Pages 1 to 4, and 1001 to 1004 supersedes Pages 1 to 3 and 1001 to 1004 of Issue 1, dated 20 May 1946, which has been amended throughout.

#### MECHANICAL ADJUSTMENTS

1. Since all mechanical adjustments are quite straightforward no detailed information is given. (Layout diagrams, coil and transformer winding details are given in Figs. 1002-1005 and Table 1002).

#### ALIGNMENT AND CALIBRATION

- 2. The following apparatus is required:-
  - (a) One set of nine coils (Coils, calibrating, Nos. 4-12).
  - (b) One differential capacity meter. This should be manufactured locally; circuit and component details are given in Fig. 1001 and Table 1001.
  - (c) One radio receiver covering the frequency band 3-10Mc/s.
  - (d) One wavemeter covering the band 3-10Mc/s and of greater accuracy than 10 parts in 10. (Wavemeter, standard, No. 2).
  - (e) One output meter for use with the receiver, as described in sub-para. 2(c).
- 3. Each of the set of coils has been accurately checked, and a table, giving details of their relevant electrical characteristics, is pasted inside the lid of the box. The electrical quantities concerned are:-
  - (a) The equivalent parallel resistance (E.P.R.).
  - (b) The frequency of oscillation in a standard Crystal test set, type A.M. 193.

The table shows these values for each coil at each setting of the switch S2.

- 4. The alignment and calibration of the test set is divided into two stages:-
  - (a) Adjusting and balancing the input capacities tuning the crystal.
  - (b) Calibrating the EQUIVALENT PARALLEL RESISTANCE scale.

#### Input capacity adjustments

- 5. The simplified input circuit is shown in Fig. 1. The instrument caters for three separate input capacities, 20, 30 and 50pF so that CK and CY have values of 40, 60 and 100pF accordingly. Since CK and CY are also affected by the Miller effect of the valve and other stray capacities, they must be adjusted, finally, under normal working conditions. This stage in the alignment thus falls into two operations:
  - (a) Measuring and balancing CK and CY under COLD conditions.
  - (b) Final trimming of CY under working conditions.

The actual condensers involved in these adjustments are shown in the simplified circuit diagrams in Tels. Z 562/1.

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Page 1

## Measured values of CK and CY

6. To allow for stray capacities, etc., the trimmer condensers should be adjusted to the following values:-

Switch position	CK, CY	Condensers involved		
		CK CY		
20pF	39.5pF	C6 and C5		
30pF	59.1pF	(06+015) and (05+016)		
50pF	71.0pF	(C6+C13) and (C5+C14)		

7. These adjustments can be made by means of a capacity bridge, or Q meter, measuring the capacitance between each terminal of the crystal socket and the chassis. In the case of CK, however, the anode load resistor, R8, together with C3 provides a shunt impedance of approximately 51kΩ at normal operating frequencies. It is desirable to measure CK without removing R8, and this can be done by means of the differential capacity meter described in para. 16.

## Final trimming under working conditions

- 8. Switch on the test set and allow it to warm up for 15 minutes. Plug coil No. 4 into the crystal socket, and with switch S2 on the position '20', adjust the amplitude control, R5, to give a reading of  $50\mu\text{A}$ , or maximum grid current.
- 9. Note the frequency of oscillation of the coil, for this setting of S2, from the table. Set the wavemeter accurately

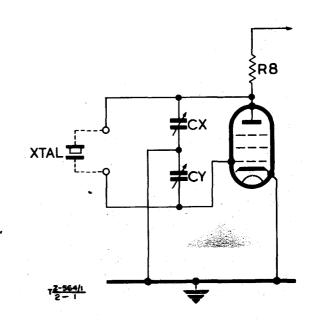


Fig. 1 - Simplified circuit of input condenser

to this frequency. Using the receiver as a normal detector, beat the wavemeter with the test set signal, via the COUPLING socket. Adjust the trimmers, C5 and C6, until the test set oscillatory circuit is tuned exactly to the wavemeter. The amplitude control R5 should be varied, if necessary, in order to maintain the grid current at 50µA, or maximum. The capacitors, C5 and C6, should be adjusted so as to be approximately equal in value, in order to balance the capacities from anode/ground and grid/ground.

- 10. When the correct frequency has been obtained, lock the trimmers.
- 11. Switch S2 to the position '30', set the wavemeter to the corresponding coil frequency and repeat the procedure, adjusting trimmers, C15 and C16, and leaving C5 and C6 unaltered. Lock C15 and C16 when the correct setting has been found.

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12. Repeat the procedure for S2 in the position '50', adjusting by means of trimmers, Cl3 and Cl4, at the appropriate coil frequency. Other trimmers should be unaltered and trimmers. Cl3 and Cl4, locked when the correct setting has been found.

# Calibration of EQUIVALENT PARALLEL RESISTANCE

13. The EQUIVALENT PARALLEL RESISTANCE scale is calibrated from μkΩ to 150kΩ, and the accuracy of calibration should be checked periodically, or following any major repairs or adjustments to the trimmers.

14. Adjustments to the reference 'loss' circuit to correspond with the calibration of the scale can be effected by means of the trimmers Cll and Cl2, and resistor R9. By using the calibrating coils a number of points on the scale for each value of • input capacitance can be obtained. Thus, the scale can be adjusted at a number of widely separated readings.

The procedure for calibration is as follows:-

Switch the test set ON. Remove the press stud over the trimmer, Cll.

Close the vacuum of the variable condenser, ClO, and make sure the dial (b)

reads maximum. If not, adjust it to do so.
Select a coil of low E.P.R., note its value at 30pF, from the table, and insert it in the crystal sockets. Set the switch S2 to position '30' and adjust the AMPLITUDE control until the meter reads a grid current of 50μA, or maximum, whichever is the lower.

Switch to position 'Z' and set the EQUIVALENT PARALLEL RESISTANCE dial to (d) the appropriate E.P.R. value for the coil. Adjust Cll by means of an

insulated screwdriver until the meter again reads 50µA.

(e) Return S2 to the '30' position, and ensure that the meter reading is still 50μA, adjusting the AMPLITUDE control if necessary, and repeat as described in sub-paras. (d) and (e).

Replace the press stud and turn the amplitude control to minimum.

Select a coil of high E.P.R., note its value at 30pF and insert it in the crystal sockets. Proceed as detailed in sub-para. (c).

Switch to position 'Z' and set the EQUIVALENT PARALLEL RESISTANCE dial to the appropriate E.P.R. value for the coil. Adjust the cylindrical trimmer, Cl2, until the meter reads 50µA.

Repeat as detailed in sub-paras. (c)-(h) to ensure that adjustment of C12

has not upset the adjustment of Cll.

Insert a coil of E.P.R. value, at 30pF, equal to approximately mid-scale, and check that the mid-scale value is correct. Adjustments to the midscale calibration can be made by changing resistor R9. If this is done, details as described in sub-paras. (c)-(h) will have to be repeated.

Using all the coils in turn, check the calibration for as many points as (1)possible for all three positions of S2, i.e., '20', '30' and '50'. Any adjustments necessary should be made by the trimmer, C11, for low values of E.P.R., and by the trimmer, Cl2, for above mid-scale values of E.P.R.

#### Differential capacity meter

16. The differential capacity meter is an instrument capable of ensuring accurately the values of capacities up to 100pF (having very poor power factors); the accuracy is + 0.2pF. In principle, the meter consists of an oscillator, preferably crystalcontrolled, of the Colpitts type feeding R.F. at 750kc/s into a tuned circuit, the resonance of which is indicated by the valve voltmeter across the tuning capacitor as shown in Fig. 1001. Across the tuning capacitor is another 100pF polar variable

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capacitor for zero adjustment, and also the terminals to which the external capacitance to be measured can be connected. The coil (I<sub>1</sub>) is wound on a No. 2 Trolitul former and mounted on a No. 2 Gecalloy iron core, and it tunes to 750kc/s with 200pF. Its Q is about 300. One of the two variable capacitors is fitted with a 0-100 slow-motion dial. In the calibration procedure this is set to the 0 position with the capacitor vanes fully meshed, and the apparatus tuned to resonance by means of the other variable (set zero) capacitor. The capacitor to be measured is then connected to the position marked X in Fig. 1001 and the slow-motion dial is varied to retune to resonance. This dial can be calibrated to give direct readings in pF; the difference between its zero setting and new position thus indicates the capacity across the input terminals. In practice, this device has been found to give accurate readings when the parallel resistance across the capacitor is only a few thousand ohm.

# Use of set of three coils (Coils calibrating Nos. 4, 8 and 12)

17. In order to check the input capacity and E.P.R. of Crystal test set, type A.M. 193, a set of three coils only, Coils calibrating Nos. 4, 8 and 12, is available. These three coils will give three widely spaced points on the E.P.R. scale for each setting of C2. The method of calibration is identical with that already outlined.

Note: The next page is Page 1001.

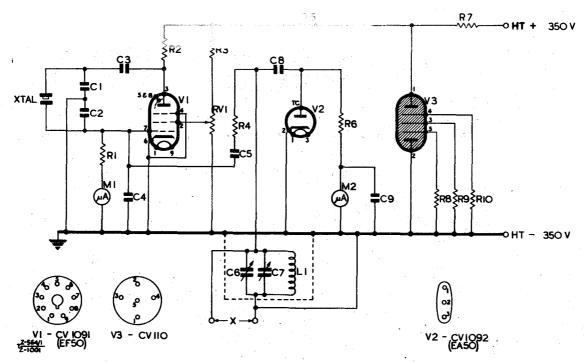


Fig. 1001 - Circuit of differential capacity meter

Fig. 1001 - Circuit of differential capacity meter							
Circuit reference	Value	Tolerance	Rating	Circuit reference	Value	Tolerance	Rating
Condensers C1 C2 C3 C4	50pF 50pF 0 .00 1uF 0 .1uF	± 5% + 5% + 20% + 20% ± 20%	350V 250V	C6 C7 C8 C9	100pF 100pF 100pF 0.1uF	Variable Variable 士 20% 士 20%	250 <b>y</b>
C4 C5	0.001uF	± 20%	250 <b>V</b>		0. 11.	_ ~ ~ ~ ~	2007
Resistors R1 R2 R3 R4 R5 R6	100kg 50kg 100kg 50kg 2kg 100kg	± 10% + 20% + 20% + 5% ± 20%	±W 1W 1W ±W 10W ±W	R7 R8 R9 R10 RV1	2166 57166 100166 200166 100166	# 20% # 20% # 20% # 20% # 20% Potentio- meter	10w ½W ½W 1w
Inductors L1							
Crystal XTAL	750kc/s						
Meters M1 M2	0-250ua 0-100ua				Assessment of the control of the con		
Valves V1 V2		CV 1091 CV 1092		<b>V3</b>	117 mm. (BD. CETONIF may care as a environment	CV 110	

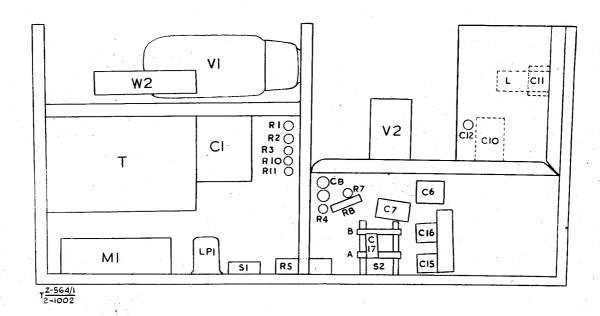


Fig. 1002 - Component layout

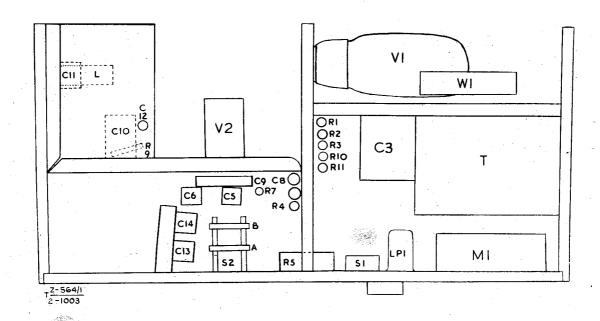


Fig. 1003 - Component layout

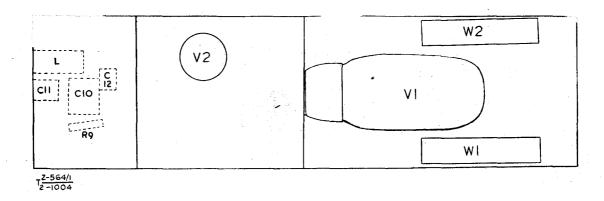


Fig. 1004 - Component layout

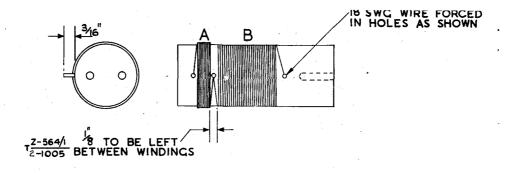


Fig. 1005 - Winding details of coil L

Transformer T					
Secondary	Winding 1	52 turns 18 S.W.G. enamelled copper wire - 6.75V, 0.6A			
	Winding 2	1,870 turns 38 S.W.G. enamelled copper wire - 230V, 40mA			
, sku s	Winding 3	Screen			
Primary	Winding 4	560 turns 28 S.W.G. enamelled copper wire + 1,155 32 S.W.G. enamelled copper wire, tapped at 240 and 765 turns			
Laminations		M and EA 24A			
Tolerances	$6k\Omega$ load $11.25\Omega$ load	230V ± 2% on 40mA 6.75V ± 2% on 0.6A			
Coil I <sub>1</sub> (see Fig. 1005)					
Section A To be wound on 1 in. diameter former with 20 turns of 36 S.W.G enamelled copper wire with turns touching					
Section B To be wound with 50 turns of 30 S.W.G. enamelled copper wire in opposite direction to section A					

Table 1002 - Winding details of coil L1 and transformer T

END

ELECTRICAL AND MECHANICAL ENGINEERING REGULATIONS
(By Command of the Army Council)

## TEST SET, CRYSTAL, TYPE AN 193

## TECHNICAL HANDBOOK - MISCELLANEOUS INSTRUCTION

## Redesignation of EMERs

## Information

- 1. To maintain the proper sequence of EMER numbers, it is intended that:-
  - (a) all future issues of EMERs on this equipment will be published in the series Tels Z 680 Z 689; and
  - (b) the current EMERs will be redesignated.

## Action

2. The following EMERs will be redesignated as shewn.

Present designation					AT STATE OF THE ST
The same of the sa	EMER designation (a)	Pages (b)	Issue No. (c)	Date (d)	New designation (e)
1	Tels Z 560/1	1	1	16 May 46	Tels Z 680
2	Tels Z 561/1	1 - 2	1	1 Jul 46	Tels Z 681
3	Tels Z 562/1	1 <b>-</b> 3 1001 <b>-</b> 1002	1	20 May 46 20 May 46	Tels Z 682
4	Tels Z 563/1	. 1	1	30 Jun 46	Tels Z 683
5	Tels Z 561/1	1 <b>-</b> 4 1001 <b>-</b> 1004	2 2	15 Sep 49 15 Sep 49	Tels Z 684 🗸

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END